



288/142  
Atty. Dkt. No. 039153-0405 (F0945) Letter  
to  
Draftsmen

Applicant: Uzodinma Okoroanyanwu et al.

Title: IMPROVING SEM INSPECTION  
AND ANALYSIS OF PATTERNED  
PHOTORESIST FEATURES

Appl. No.: 09/820,143 ✓

Filing Date: 03/28/2001 ✓

Examiner: Unknown

Art Unit: 2878

<b>CERTIFICATE OF MAILING</b> I hereby certify that this correspondence is being deposited with the United States' Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on the date below.  Deborah A. Kocorowski (Printed Name)  Deborah A. Kocorowski (Signature)  June 11, 2001 (Date of Deposit)
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**TRANSMITTAL OF FORMAL DRAWINGS**

Commissioner for Patents  
Washington, D.C. 20231

ATTENTION: DRAWING REVIEW BRANCH

Sir:

Transmitted herewith are the formal drawings (4 sheets, Figures 1-5) for the  
above-identified application. The Official Draftsperson is respectfully requested to  
approve these drawings for entry into the application.

Respectfully submitted,

Date 6/11/2001

By Katherine Lee

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JUN 25 2001  
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